### SN54ABT16861, SN74ABT16861 **20-BIT BUS TRANSCEIVERS** WITH 3-STATE OUTPUTS SCBS455 - OCTOBER 1992

<ul> <li>Members of the Texas Instruments Widebus<sup>™</sup> Family</li> </ul>	SN54ABT16861 SN74ABT16861 (TOP V	DL PACKAGE
<ul> <li>State-of-the-Art EPIC-IIB ™ BiCMOS Design Significantly Reduces Power Dissipation</li> </ul>		56 10EBA
<ul> <li>Latch-Up Performance Exceeds 500 mA Per</li></ul>	1B1 🛛 2	55 ] 1A1
JEDEC Standard JESD-17	1B2 🗖 3	54 ] 1A2
<ul> <li>Typical V<sub>OLP</sub> (Output Ground Bounce) &lt; 1 V</li></ul>	GND <b>[</b> ] 4	53 GND
at V <sub>CC</sub> = 5 V, T <sub>A</sub> = 25°C	1B3 <b>[</b> ] 5	52 1A3
<ul> <li>Distributed V<sub>CC</sub> and GND Pin Configuration</li></ul>	1B4 [] 6	51 ] 1A4
Minimizes High-Speed Switching Noise	V <sub>CC</sub> [] 7	50 ] V <sub>CC</sub>
<ul> <li>Flow-Through Architecture Optimizes PCB Layout</li> </ul>	1B5 8 1B6 9 1B7 10	49 1A5 48 1A6 47 1A7
<ul> <li>High-Drive Outputs (-32-mA I<sub>OH</sub>,</li></ul>	GND [ 11	46 GND
64-mA I <sub>OL</sub> )	1B8 [ 12	45 1A8
<ul> <li>Packaged in Plastic 300-mil Shrink</li></ul>	1B9 🛛 13	44 ] 1A9
Small-Outline Packages (DL) and 380-mil	1B10 🖸 14	43 ] 1A10
Fine-Pitch Ceramic Flat Packages (WD) Using 25-mil Center-to-Center Spacings	2B1 15 2B2 16 2B3 17	42 2A1 41 2A2 40 2A3
description	GND 🛛 18	39 🛛 GND
The 'ABT18861 is a 20-bit transceiver designed	2B4 [ 19	38 2A4
for asynchronous communication between data	2B5 [ 20	37 2A5
buses. The control function implementation allows	2B6 [ 21	36 2A6
for maximum flexibility in timing.	V <sub>CC</sub> [ 22	35 V <sub>CC</sub>
The 'ABT16861 can be used as two 10-bit transceivers or one 20-bit transceiver. It allows data transmission from the A bus to the B bus or from the B bus to the A bus depending upon the logic levels at the output-enable (OEAB and OEBA) inputs.	2B7 [ 23 2B8 [ 24 GND [ 25 2B9 [ 26 2B10 [ 27 2OEAB [ 28	34 2A7 33 2A8 32 GND 31 2A9 30 2A10 29 2OEBA

To ensure the high-impedance state during power up or power down, OE should be tied to V<sub>CC</sub> through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ABT16861 is packaged in TI's shrink small-outline package (DL), which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The SN54ABT16861 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ABT16861 is characterized for operation from -40°C to 85°C.

(each 10-bit section)							
INF	PUTS	OPERATION					
OEAB	OEBA	OFERATION					
L	Н	A data to B bus					
н	L	B data to A bus					
н	Н	Isolation					
L	L	Latch A and B (A = B)					

#### **FUNCTION TABLE** (each 10-bit section)

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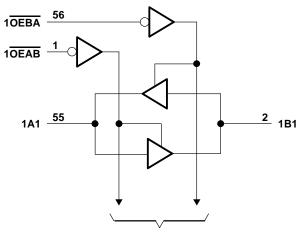
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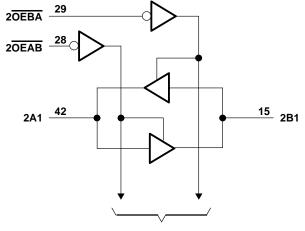
## SN54ABT16861, SN74ABT16861 20-BIT BUS TRANSCEIVERS WITH 3-STATE OUTPUTS

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## logic diagram (positive logic)



To 9 Other Channels



**To 9 Other Channels** 

#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

	,
Supply voltage range, V <sub>CC</sub>	–0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high state or power-off state, V <sub>O</sub>	-0.5 V to 5.5 V
Current into any output in the low state, IO: SN54ABT16861	96 mA
SN74ABT16861	128 mA
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)	–18 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0)	–50 mA
Maximum power dissipation at T <sub>A</sub> = 55°C (in still air)	1 W
Storage temperature range	-65°C to 150°C

<sup>+</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.



### recommended operating conditions (see Note 2)

		SN54AB	T16861	SN74ABT16861		UNIT	
			MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage		4.5	5.5	4.5	5.5	V
VIH High-level input voltage					2		V
VIL	VIL Low-level input voltage					0.8	V
VI Input voltage				VCC	0	VCC	V
IOH High-level output current				-24		-32	mA
IOL	IOL Low-level output current					64	mA
$\Delta t / \Delta v$	Input transition rise or fall rate	Outputs enabled		10		10	ns/V
Т <sub>А</sub>	T <sub>A</sub> Operating free-air temperature				-40	85	°C

NOTE 2: Unused or floating inputs must be held high or low.

#### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEST CONDITIONS			т	A = 25°	0	SN54ABT16861		SN74ABT16861				
PARAMETER				MIN	түр†	MAX	MIN	MAX	MIN	MAX	UNIT		
VIK	V <sub>CC</sub> = 4.5 V,	lj = -18 mA			-1.2		-1.2		-1.2	V			
	V <sub>CC</sub> = 4.5 V,	$V_{CC} = 4.5 \text{ V}, \qquad I_{OH} = -3 \text{ mA}$					2.5		2.5				
<b>M a a a</b>	$V_{CC} = 5 V$ , $I_{OH} = -3 mA$			3			3		3		v		
VOH	$V_{CC} = 4.5 \text{ V}, \qquad I_{OH} = -24 \text{ mA}$			2			2						
	$V_{CC} = 4.5 \text{ V}, \qquad I_{OH} = -32 \text{ mA}$			2‡					2				
Ve	$V_{CC} = 4.5 \text{ V}, \qquad I_{OL} = 48 \text{ mA}$					0.55		0.55			v		
VOL	V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 64 mA					0.55‡				0.55	v		
1.	V <sub>CC</sub> = 5.5 V,		Control inputs			±1		±1		±1	±1 μA		
Ι	$V_I = V_{CC}$ or GND				±100		±100		±100	μΑ			
IOZH <sup>§</sup>	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.7 V				50		50		50	μΑ		
IOZL <sup>§</sup>	$V_{CC} = 5.5 \text{ V}, \qquad V_{O} = 0.5 \text{ V}$					-50		-50		-50	μA		
IOFF	$V_{CC} = 0 V,$	$V_{I} \text{ or } V_{O} \leq 4.$	5 V			±100				±100	μΑ		
ICEX	V <sub>CC</sub> = 5.5 V,	VO = 5.5 V	Outputs high			50		50		50	μΑ		
۱ <sub>0</sub> ¶	V <sub>CC</sub> = 5.5 V,	VO = 2.5 V		-50	-100	-180	-50	-180	-50	-180	mA		
	V <sub>CC</sub> = 5.5 V,		Outputs high			2		2		2			
ICC	I <sub>O</sub> = 0,	A or B ports	Outputs low			32		32		32	mA		
	$V_I = V_{CC}$ or GND		Outputs disabled			2		2		2			
∆ICC#	V <sub>CC</sub> = 5.5 V, One	Data inputa	Outputs enabled			1		1.5		1			
	input at 3.4 V, Data inputs Other inputs at	Outputs disabled			0.05		0.05		0.05	mA			
	V <sub>CC</sub> or GND Control inputs					1.5		1.5		1.5	]		
Ci	VI = 2.5 V or 0.5 V Control inputs									pF			
C <sub>io</sub>	$V_{O} = 2.5 \text{ V or } 0.5 \text{ V}$ A or B ports										pF		

<sup>†</sup> All typical values are at V<sub>CC</sub> = 5 V.
<sup>‡</sup> On products compliant to MIL-STD-883, Class B, this parameter does not apply.

§ The parameters IOZH and IOZL include the input leakage current.

¶ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

<sup>#</sup> This is the increase in supply current for each input that is at the specified TTL voltage level rather than V<sub>CC</sub> or GND.

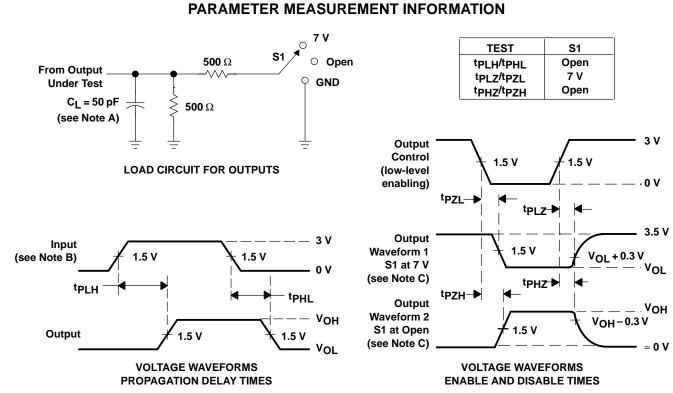


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switching characteristics over recommended ranges of supply voltage and operating free-air temperature,  $C_L = 50 \text{ pF}$  (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 5 V, T <sub>A</sub> = 25 °C		SN54ABT16861 SN74ABT16861		Г16861	UNIT		
	(	(0011 01)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
<sup>t</sup> PLH	A or B	B or A								ns
<sup>t</sup> PHL		BUIA								
<sup>t</sup> PZH	OEAB or OEBA	A B or A								ns
<sup>t</sup> PZL										115
<sup>t</sup> PHZ	OEAB or OEBA	B or A								ns
<sup>t</sup> PLZ										115



NOTES: A. CL includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>0</sub> = 50  $\Omega$ , t<sub>f</sub>  $\leq$  2.5 ns, t<sub>f</sub>  $\leq$  2.5 ns. C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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